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**IEC 60689**

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# **INTERNATIONAL STANDARD**

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**Measurement and test methods for tuning fork quartz crystal units in the range from 10 kHz to 200 kHz and standard values**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

PRICE CODE

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## CONTENTS

FOREWORD.....	4
1 Scope.....	6
2 Normative references .....	6
3 Overview .....	6
3.1 General.....	6
3.2 Applied frequency range.....	6
3.3 Measurement method.....	6
3.4 Load capacitance .....	7
3.5 Recommended drive level .....	7
3.6 Measurement conditions.....	7
3.7 Measurement of frequency-temperature characteristics.....	7
3.8 Load capacitance frequency characteristics .....	7
4 Measurement methods .....	7
4.1 Method A.....	7
4.1.1 Vector network analyzer/vector impedance analyzer.....	7
4.1.2 Block diagram.....	7
4.1.3 Specifications for vector network analyzer/vector impedance analyzer .....	8
4.1.4 Test fixture .....	8
4.1.5 Measurement of equivalent circuit constants .....	9
4.1.6 Frequency pulling .....	10
4.2 Method B.....	10
4.2.1 General .....	10
4.2.2 Block diagram.....	10
4.2.3 Calibration.....	11
4.2.4 Procedure.....	12
5 Measurement conditions.....	12
5.1 General.....	12
5.2 Measurement conditions.....	12
5.3 Measurement of the frequency-temperature dependence .....	13
5.3.1 General .....	13
5.3.2 Block diagram.....	13
5.3.3 Determination of the turnover point and parabolic coefficient $\beta$ (standard reference method) .....	14
5.3.4 Measurement of the frequency versus temperature characteristics (mass production method) .....	14
5.3.5 Frequency $C_L$ curve.....	15
6 Test and environmental examination .....	15
6.1 Application of the definition of IEC 60122-1.....	15
6.2 Magnetism – Influence of a magnetic field on the frequency.....	16
6.3 Enclosure.....	16
6.4 Measuring conditions and electric performance .....	16
6.4.1 General .....	16
6.4.2 Measurement conditions.....	16
6.4.3 Standard values .....	16
Bibliography.....	18

Figure 1 – Block diagram of the measurement method using the vector network analyzer or vector impedance analyzer .....	8
Figure 2 – Block diagram of test fixture .....	9
Figure 3 – Block diagram of test fixture (including a load capacitance).....	9
Figure 4 – Block diagram of test fixture for bridge method .....	11
Figure 5 – Block diagram of test fixture for bridge method (including a load capacitance) .....	11
Figure 6 – Block diagram of measurement of the frequency-temperature dependence .....	13
Figure 7 – Frequency–temperature template (Turnover point: $25 \pm 5 \text{ }^\circ\text{C}$ , $\beta = -45 \times 10_{-9}/^\circ\text{C}_2$ ) .....	14
Figure 8a) – $\Delta f/f$ versus $C_L$ curve .....	15
Figure 8b) – $\Delta f/f$ versus $C_L$ curve .....	15
Figure 8 – $\Delta f/f$ versus $C_L$ curve with different $C_{Ls}$ .....	15
Table 1 – Specifications for vector network analyzer/vector impedance analyzer .....	8
Table 2 – Standard values .....	17

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

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# MEASUREMENT AND TEST METHODS FOR TUNING FORK QUARTZ CRYSTAL UNITS IN THE RANGE FROM 10 kHz TO 200 kHz AND STANDARD VALUES

### FOREWORD

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International Standard IEC 60689 has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

This second edition cancels and replaces the first edition published in 1980. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) The title of the first edition is *Measurements and test methods for 32 kHz quartz crystal units for wrist watches and standard values*. The title is modified and the frequency range of this second edition is extended to the range from 10 kHz to 200 kHz.
- b) The Lissajous method is defined in the first edition as the standard measurement method. The PI network and bridge method are used in this second edition.
- c) The PI network has a transformer for impedance matching. This composition differs from that of IEC 60444-1.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/809/FDIS	49/815/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition; or
- amended.

A bilingual version of this publication may be issued at a later date.

# MEASUREMENT AND TEST METHODS FOR TUNING FORK QUARTZ CRYSTAL UNITS IN THE RANGE FROM 10 kHz TO 200 kHz AND STANDARD VALUES

## 1 Scope

This International Standard applies to measurements and test methods for tuning fork quartz crystal units in the range from 10 kHz to 200 kHz and standard values for frequency control and selection.

## 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050-561, *International Electrotechnical Vocabulary – Chapter 561: Piezoelectric devices for frequency control and selection*

IEC 60122-1, *Quartz crystal units of assessed quality – Part 1: Generic specification*

IEC 60122-3, *Quartz crystal units of assessed quality – Part 3: Standard outlines and lead connections*

IEC 60444 (series), *Measurement of quartz crystal unit parameters by zero phase technique in a  $\pi$ -network*

IEC 60617, *Graphical symbols for diagrams*

ISO 1000:1992, *SI units and recommendations for the use of their multiples and certain other Units*